

## PSG INSTITUTE OF ADVANCED STUDIES

### Nanotech Research, Innovation and Incubation centre

#### Rules and Charges of SPM Facility Usage

##### 1. Multimode Scanning Probe Microscope, AFM/STM (NT-MDT)

AFM Imaging: Contact / Semi-contact mode

*Special Techniques available:*

*In Air and Vacuum:* Scanning Tunneling Microscopy (STM), Lateral Force Microscopy (LFM), Phase Imaging, Force Modulation, Magnetic Force Microscopy (MFM), Adhesion force imaging, AFM Lithography, Spreading Resistance Imaging (SRI), Scanning Kelvin Probe Microscopy (SKM), Heating Stage Operations, Nanosclerometry with AFM-Nanoindentation.

*In Liquid:* Contact AFM/LFM/Adhesion Force Imaging/Force Modulation, Resonant Mode, Phase Imaging, AFM Lithography, Electrochemical AFM/STM Imaging

Faculty in charge: Dr. P.Biji, Assistant Professor in Nanotechnology, PSGIAS

Email: [pbm@psgias.ac.in](mailto:pbm@psgias.ac.in)

**Researchers from various institutions are welcome to use these facilities. Those who want to avail these facilities are requested to send the filled job requisition form (Downloadable from PSGIAS website) and advance DD/Cheque (if applicable) in favour of “PSG Centre for Sponsored Research & Consultancy” payable at Coimbatore to:**

Mrs. Uma Maheswari

PSG Institute of Advanced Studies

PB No: 1609, Peelamedu

Coimbatore-641 004

E-mail: [uma@psgias.ac.in](mailto:uma@psgias.ac.in), Phone: 0422-4344000 (Extn: 4541)

#### Rules and Charges for using the facility

1. To avail any facility prior registration is a must.
2. Analysis will be done on charge basis.
3. Appointment will be given as per queue and the allotted time for the slot will be informed through E-mail.
4. For a better analysis, basic details about the sample should be given.
5. Refunds will not be made in any case.
6. Sample preparation should be done by the user.
7. External colleges & Universities and industry users should pay the charges in advance along with the samples for characterization

## 8. Analysis Charges:

### Multimode SPM (NTMDT)-Imaging and Special techniques- Basic analysis charges

<b>Modes</b>	<b>Internal (PSG Institutions (INR))</b>	<b>External Colleges &amp; Universities (INR)</b>	<b>Industry (INR)</b>
<b>Atomic Force Microscopy (AFM)</b>	500	1500	3000
<b>Lateral Force Microscopy (LFM)</b>	500	1500	3000
<b>Spreading Resistance Imaging (SRI)</b>	500	1600	3200
<b>Force Modulation mode</b>	500	1500	3000
<b>Phase imaging</b>	500	1500	3000
<b>Adhesion Force Imaging</b>	400	1200	2400
<b>Magnetic Force Microscopy (MFM)</b>	600	2000	4000
<b>Kelvin Probe Microscopy</b>	600	2000	4000
<b>Heating Stage operations</b>	600	2000	4000
<b>Nanoindentation</b>	600	2000	4000
<b>Liquid stage Operations</b>	600	2000	4000
<b>In Vacuum condition</b>	600	2000	4000
<b>Scanning Tunneling Microscopy</b>	600	2000	4000
<b>Electrochemical AFM/STM</b>	1000	3000	6000
<b>Lithography</b>	600	2000	4000

**Note: 18% GST to be added to these basic charges**